## Features

- Fast Read Access Time 45 ns
- Low-Power CMOS Operation
  - 100 µA Max Standby
- 25 mA Max Active at 5 MHz
- JEDEC Standard Packages
  - 32-lead PDIP
  - 32-lead PLCC
  - 32-lead TSOP
- 5V ± 10% Supply
- High Reliability CMOS Technology
  - 2000V ESD Protection
  - 200 mA Latchup Immunity
- Rapid Programming Algorithm 100 µs/Byte (Typical)
- CMOS and TTL Compatible Inputs and Outputs
- Integrated Product Identification Code
- Industrial Temperature Range
- Green (Pb/Halide-free) Packaging Option

## 1. Description

The AT27C010 is a low-power, high-performance 1,048,576-bit one-time programmable read-only memory (OTP EPROM) organized as 128K by 8 bits. They require only one 5V power supply in normal read mode operation. Any byte can be accessed in less than 45 ns, eliminating the need for speed reducing WAIT states on high-performance microprocessor systems.

In read mode, the AT27C010 typically consumes only 8 mA. Standby mode supply current is typically less than 10 µA.

The AT27C010 is available in a choice of industry-standard JEDEC-approved onetime programmable (OTP) plastic PDIP, PLCC, and TSOP packages. All devices feature two line control ( $\overline{CE}$ ,  $\overline{OE}$ ) to give designers the flexibility to prevent bus contention.

With 128K byte storage capability, the AT27C010 allows firmware to be stored reliably and to be accessed by the system without the delays of mass storage media.

Atmel's AT27C010 has additional features to ensure high quality and efficient production use. The Rapid Programming Algorithm reduces the time required to program the part and guarantees reliable programming. Programming time is typically only 100  $\mu$ s/byte. The Integrated Product Identification Code electronically identifies the device and manufacturer. This feature is used by industry-standard programming equipment to select the proper programming algorithms and voltages.



1-Megabit (128K x 8) OTP EPROM

## AT27C010

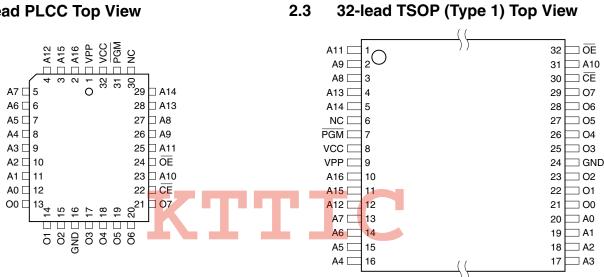
0321M-EPROM-12/07



#### **Pin Configurations** 2.

Pin Name	Function
A0 - A16	Addresses
00 - 07	Outputs
CE	Chip Enable
ŌĒ	Output Enable
PGM	Program Strobe
NC	No Connect

#### 2.1 32-lead PLCC Top View



2.3

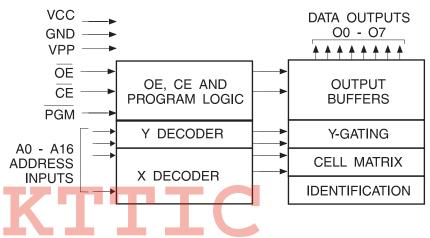
#### 2.2 **32-lead PDIP Top View**

		<u> </u>		1
		$\bigcirc$	~~	
VPP [	1		32	
A16 🗆	2		31	🗆 PGM
A15 🗆	3		30	□ NC
A12 🗆	4		29	🗆 A14
A7 🗆	5		28	🗆 A13
A6 🗆	6		27	🗆 A8
A5 🗆	7		26	🗆 A9
A4 🗆	8		25	🗆 A11
A3 🗆	9		24	□ OE
A2 🗆	10		23	🗆 A10
A1 🗆	11		22	□ CE
A0 🗆	12		21	07
O0 🗆	13		20	□ O6
01 🗆	14		19	🗆 O5
O2 🗆	15		18	<b>□</b> 04
GND 🗆	16		17	🗆 O3

## 3. System Considerations

Switching between active and standby conditions via the Chip Enable pin may produce transient voltage excursions. Unless accommodated by the system design, these transients may exceed datasheet limits, resulting in device non-conformance. At a minimum, a 0.1  $\mu$ F high frequency, low inherent inductance, ceramic capacitor should be utilized for each device. This capacitor should be connected between the V<sub>CC</sub> and Ground terminals of the device, as close to the device as possible. Additionally, to stabilize the supply voltage level on printed circuit boards with large EPROM arrays, a 4.7  $\mu$ F bulk electrolytic capacitor should be utilized, again connected between the V<sub>CC</sub> and Ground terminals. This capacitor should be positioned as close as possible to the point where the power supply is connected to the array.

## 4. Block Diagram



## 5. Absolute Maximum Ratings\*

Temperature Under Bias55°C to +125°C
Storage Temperature
Voltage on Any Pin with Respect to Ground2.0V to +7.0V <sup>(1)</sup>
Voltage on A9 with Respect to Ground2.0V to +14.0V <sup>(1)</sup>
$V_{\text{PP}}$ Supply Voltage with Respect to Ground2.0V to +14.0V^{(1)}

\*NOTICE:

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Note: 1. Minimum voltage is -0.6V DC which may undershoot to -2.0V for pulses of less than 20 ns. Maximum output pin voltage is  $V_{CC}$  + 0.75V DC which may overshoot to +7.0 volts for pulses of less than 20 ns.





## 6. Operating Modes

Mode/Pin	CE	OE	PGM	Ai	V <sub>PP</sub>	Outputs
Read	V <sub>IL</sub>	V <sub>IL</sub>	X <sup>(1)</sup>	Ai	Х	D <sub>OUT</sub>
Output Disable	Х	V <sub>IH</sub>	Х	X	х	High Z
Standby	V <sub>IH</sub>	Х	Х	Х	Х	High Z
Rapid Program <sup>(2)</sup>	V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IL</sub>	Ai	V <sub>PP</sub>	D <sub>IN</sub>
PGM Verify	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IH</sub>	Ai	V <sub>PP</sub>	D <sub>OUT</sub>
PGM Inhibit	V <sub>IH</sub>	Х	Х	X	V <sub>PP</sub>	High Z
Product Identification <sup>(4)</sup>	V <sub>IL</sub>	V <sub>IL</sub>	x	$A9 = V_{H}^{(3)}$ $A0 = V_{IH} \text{ or } V_{IL}$ $A1 - A16 = V_{IL}$	x	Identification Code

Note: 1. X can be  $V_{IL}$  or  $V_{IH}$ .

2. Refer to Programming Characteristics.

- 3.  $V_{H} = 12.0 \pm 0.5 V.$
- Two identifier bytes may be selected. All Ai inputs are held low (V<sub>IL</sub>), except A9 which is set to V<sub>H</sub> and A0 which is toggled low (V<sub>IL</sub>) to select the Manufacturer's Identification byte and high (V<sub>IH</sub>) to select the Device Code byte.

## 7. DC and AC Operating Conditions for Read Operation

		AT27	C010
		-45	-70
Operating Temp. (Case)	Ind.	-40° C - 85° C	-40° C - 85° C
V <sub>CC</sub> Power Supply		5V ± 10%	$5V\pm10\%$

## 8. DC and Operating Characteristics for Read Operation

Symbol	Parameter	Condition		Min	Max	Units	
I <sub>LI</sub>	Input Load Current	$V_{IN} = 0V$ to $V_{CC}$	Ind.		± 1	μA	
I <sub>LO</sub>	Output Leakage Current	$V_{OUT} = 0V$ to $V_{CC}$	Ind.		± 5	μA	
IPP1 <sup>(2)</sup>	V <sub>PP</sub> <sup>(1))</sup> Read/Standby Current	$V_{PP} = V_{CC}$		10	μA		
		$I_{SB1}$ (CMOS), $\overline{CE} = V_{CC} \pm 0.3V$			100	μA	
I <sub>SB</sub>	V <sub>CC</sub> <sup>(1)</sup> Standby Current	$I_{SB2}$ (TTL), $\overline{CE}$ = 2.0 to $V_{CC}$ + 0.5V			1	mA	
I <sub>cc</sub>	V <sub>CC</sub> Active Current	$f = 5 \text{ MHz}, I_{OUT} = 0 \text{ mA}, \overline{CE}$	Ē = V <sub>IL</sub>		25	mA	
V <sub>IL</sub>	Input Low Voltage			-0.6	0.8	V	
V <sub>IH</sub>	Input High Voltage		2.0	V <sub>CC</sub> + 0.5	V		
V <sub>OL</sub>	Output Low Voltage	I <sub>OL</sub> = 2.1 mA			0.4	V	
V <sub>OH</sub>	Output High Voltage	I <sub>OH</sub> = -400 μA		2.4		V	

Note: 1.  $V_{CC}$  must be applied simultaneously or before  $V_{PP}$  and removed simultaneously or after  $V_{PP}$ 

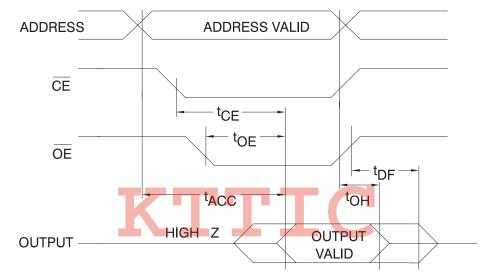
2. V<sub>PP</sub> may be connected directly to V<sub>CC</sub>, except during programming. The supply current would then be the sum of I<sub>CC</sub> and I<sub>PP</sub>

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## 9. AC Characteristics for Read Operation

				AT27C010			
			-	-45		-70	
Symbol	Parameter	Condition	Min	Max	Min	Max	Units
t <sub>ACC</sub> <sup>(3)</sup>	Address to Output Delay	$\overline{CE} = \overline{OE} = V_{IL}$		45		70	ns
t <sub>CE</sub> <sup>(2)</sup>	CE to Output Delay	$\overline{OE} = V_{IL}$		45		70	ns
t <sub>OE</sub> <sup>(2)(3)</sup>	OE to Output Delay	$\overline{CE} = V_{IL}$		20		30	ns
t <sub>DF</sub> <sup>(4)(5)</sup>	OE or CE High to Output Float, whichever occurred first			20		25	ns
t <sub>OH</sub>	Output Hold from Address, CE or OE, whichever occurred first				7		ns

## **10. AC Waveforms for Read Operation**<sup>(1)</sup>



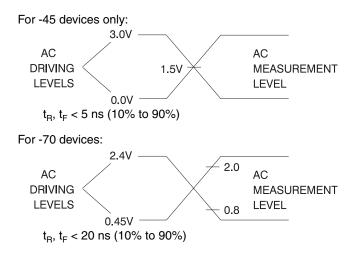
- Notes: 1. Timing measurement reference level is 1.5V for -45 devices. Input AC drive levels are  $V_{IL} = 0.0V$  and  $V_{IH} = 3.0V$ . Timing measurement reference levels for all other speed grades are  $V_{OL} = 0.8V$  and  $V_{OH} = 2.0V$ . Input AC drive levels are  $V_{IL} = 0.45V$  and  $V_{IH} = 2.4V$ .
  - 2.  $\overline{OE}$  may be delayed up to t<sub>CE</sub> t<sub>OE</sub> after the falling edge of  $\overline{CE}$  without impact on t<sub>CE</sub>.
  - 3.  $\overline{\text{OE}}$  may be delayed up to  $t_{ACC}$   $t_{OE}$  after the address is valid without impact on  $t_{ACC}$ .
  - 4. This parameter is only sampled and is not 100% tested.
  - 5. Output float is defined as the point when data is no longer driven.



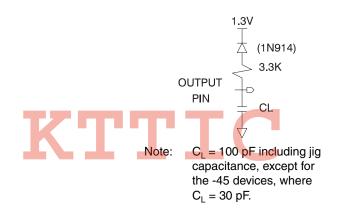




## 11. Input Test Waveforms and Measurement Levels



## 12. Output Test Load



### 13. Pin Capacitance

 $f = 1 \text{ MHz}, T = 25^{\circ}C^{(1)}$ 

Symbol	Тур	Мах	Units	Conditions
C <sub>IN</sub>	4	8	pF	$V_{IN} = 0V$
C <sub>OUT</sub>	8	12	pF	$V_{OUT} = 0V$

Note: 1. Typical values for nominal supply voltage. This parameter is only sampled and is not 100% tested.

#### READ PROGRAM (VERIFY) VIH ADDRESS STABLE ADDRESS VIL <sup>t</sup>AS <sup>– t</sup>AH <sup>t</sup>OE<sup>-</sup> VIH DATA OUT VALID DATA DATA IN VIL <sup>t</sup>DS <sup>t</sup>DH 6.5V $V_{cc}$ 5.0V - <sup>t</sup>DFP <sup>t</sup>vcs 13.0V $V_{PP}$ 5.0V <sup>t</sup>VPS <sup>t</sup>PRT VIH ĈĒ VIL <sup>t</sup>CES VIH PGM VIL <sup>t</sup>OES <sup>t</sup>PW VIH ŌĒ VIL

## 14. Programming Waveforms<sup>(1)</sup>

- Notes: 1. The Input Timing Reference is 0.8V for  $V_{IL}$  and 2.0V for  $V_{IH}$ .
  - 2.  $t_{OE}$  and  $t_{DFP}$  are characteristics of the device but must be accommodated by the programmer.
  - 3. When programming the AT27C010 at 0.1  $\mu$ F capacitor is required across V<sub>PP</sub> and ground to suppress spurious voltage transients.





## **15. DC Programming Characteristics**

 $T_{A} = 25 \pm 5^{\circ}C, \, V_{CC} = 6.5 \pm 0.25V, \, V_{PP} = 13.0 \pm 0.25V$ 

			Limits		
Symbol	Parameter	Test Conditions	Min	Max	Units
I <sub>LI</sub>	Input Load Current	$V_{IN} = V_{IL}, V_{IH}$		±10	μA
V <sub>IL</sub>	Input Low Level		-0.6	0.8	V
V <sub>IH</sub>	Input High Level		2.0	V <sub>cc</sub> + 1	V
V <sub>OL</sub>	Output Low Voltage	I <sub>OL</sub> = 2.1 mA		0.4	V
V <sub>OH</sub>	Output High Voltage	I <sub>OH</sub> = -400 μA	2.4		V
I <sub>CC2</sub>	V <sub>CC</sub> Supply Current (Program and Verify)			40	mA
I <sub>PP2</sub>	V <sub>PP</sub> Supply Current	$\overline{CE} = \overline{PGM} = V_{IL}$		20	mA
V <sub>ID</sub>	A9 Product Identification Voltage		11.5	12.5	V

## **16. AC Programming Characteristics**

 $T_A = 25 \pm 5^{\circ}C, V_{CC} = 6.5 \pm 0.25 V, V_{PP} = 13.0 \pm 0.25 V$ 

			Lin	nits	
Symbol	Parameter	Test Conditions <sup>(1)</sup>	Min	Max	Units
t <sub>AS</sub>	Address Setup Time		2		μs
t <sub>CES</sub>	CE Setup Time		2		μs
t <sub>OES</sub>	OE Setup Time	Input Rise and Fall Times (10% to 90%) 20 ns	2		μs
t <sub>DS</sub>	Data Setup Time	- (10% l0 90%) 20 hs	2		μs
t <sub>AH</sub>	Address Hold Time	Input Pulse Levels	0		μs
t <sub>DH</sub>	Data Hold Time	0.45V to 2.4V	2		μs
t <sub>DFP</sub>	OE High to Output Float Delay <sup>(2)</sup>	Input Timing Reference Level	0	130	ns
t <sub>VPS</sub>	V <sub>PP</sub> Setup Time	0.8V to 2.0V	2		μs
t <sub>vcs</sub>	V <sub>CC</sub> Setup Time		2		μs
t <sub>PW</sub>	PGM Program Pulse Width <sup>(3)</sup>	Output Timing Reference Level 0.8V to 2.0V	95	105	μs
t <sub>OE</sub>	Data Valid from OE			150	ns
t <sub>PRT</sub>	V <sub>PP</sub> Pulse Rise TIme During Programming		50		ns

Note: 1.  $V_{CC}$  must be applied simultaneously or before  $V_{PP}$  and removed simultaneously or after  $V_{PP}$ .

2. This parameter is only sampled and is not 100% tested. Output Float is defined as the point where data is no longer driven – see timing diagram.

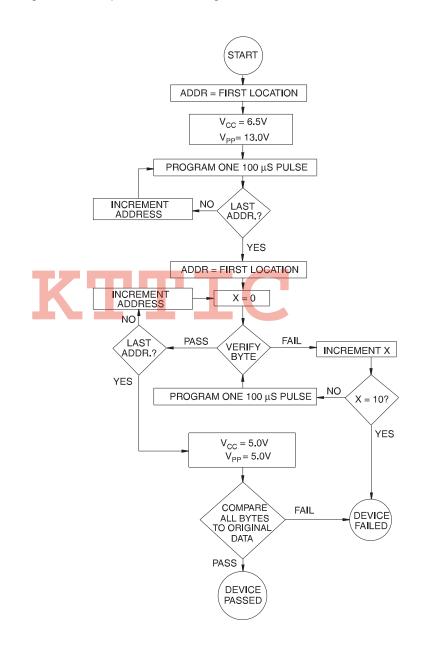
3. Program Pulse width tolerance is 100  $\mu$ sec  $\pm$  5%.

## 17. Atmel's AT27C010 Integrated Product Identification Code

		Pins						Hex		
Codes	A0	07	<b>O</b> 6	<b>O</b> 5	O4	O3	02	01	00	Data
Manufacturer	0	0	0	0	1	1	1	1	0	1E
Device Type	1	0	0	0	0	0	1	0	1	05

## 18. Rapid Programming Algorithm

A 100  $\mu$ s  $\overline{PGM}$  pulse width is used to program. The address is set to the first location. V<sub>CC</sub> is raised to 6.5V and V<sub>PP</sub> is raised to 13.0V. Each address is first programmed with one 100  $\mu$ s PGM pulse without verification. Then a verification/reprogramming loop is executed for each address. In the event a byte fails to pass verification, up to 10 successive 100  $\mu$ s pulses are applied with a verification after each pulse. If the byte fails to verify after 10 pulses have been applied, the part is considered failed. After the byte verifies properly, the next address is selected until all have been checked. V<sub>PP</sub> is then lowered to 5.0V and V<sub>CC</sub> to 5.0V. All bytes are read again and compared with the original data to determine if the device passes or fails.







## **19. Ordering Information**

## 19.1 Standard Package

t <sub>ACC</sub>	I <sub>CC</sub> (mA)				
(ns)	Active	Standby	Ordering Code	Package	Operation Range
45	25	0.1	AT27C010-45JI	32J	Industrial
			AT27C010-45PI	32P6	(-40° C to 85° C)
			AT27C010-45TI	32T	
70	25	0.1	AT27C010-70JI	32J	Industrial
			AT27C010-70PI	32P6	(-40° C to 85° C)
			AT27C010-70TI	32T	

Note:

Not recommended for new designs. Use Green package option.

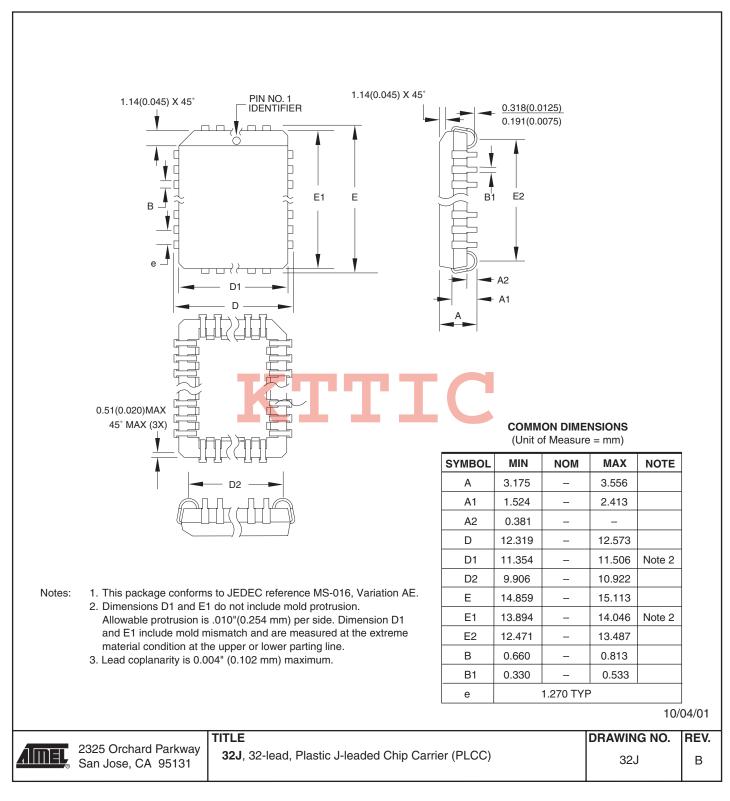
## 19.2 Green Package Option (Pb/Halide-free)

t <sub>ACC</sub> (ns)	I <sub>CC</sub> (mA)				
	Active	Standby	Ordering Code	Package	Operation Range
45	25	0.1	AT27C010-45JU	32J	Industrial
			AT27C010-45PU	32P6	(-40° C to 85° C)
			AT27C010-45TU	32T	
70	25	0.1	AT27C010-70JU	32J	Industrial
			AT27C010-70PU	32P6	(-40° C to 85° C)
			AT27C010-70TU	32T	

Package Type				
32J	32-lead, Plastic J-leaded Chip Carrier (PLCC)			
32P6	32-lead, 0.600" Wide, Plastic Dual Inline Package (PDIP)			
32T	32-lead, Plastic Thin Small Outline Package (TSOP)			

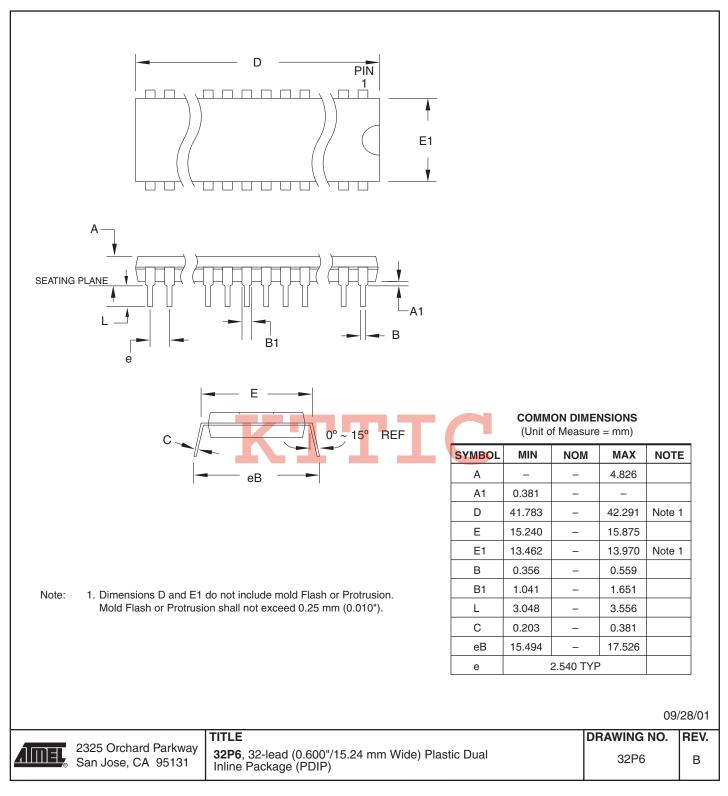
## 20. Package Information

### 20.1 32J – PLCC





### 20.2 32P6 - PDIP



### 20.3 32T – TSOP

